# PC957L0NSZ

\* VDE (VDE0884) approved type is also available as an option

#### Features

- 1. High resistance to noise (CMR:MIN. 15kV/µs)
- 2. High speed response

 $(t_{PHL}:MAX.\ 0.8\mu s,\ t_{PLH}:MAX.\ 0.8\mu s)$ 

- 3. Standard DIP type
- 4. Isolation voltage (V<sub>iso (rms)</sub>=5.0kV)
- 5. Recognized by UL, file No. E64380 (model No. PC957L)

## Applications

- 1. Programmable controller
- 2. Inverter

<b>Absolute Maximum Ratings</b> $(T_a=25^{\circ})$						
Parameter		Symbol	Rating	Unit		
Input	*1 Forward current	I <sub>F</sub>	25	mA		
	Reverse voltage	V <sub>R</sub>	5	V		
	*2 Power dissipation	Р	45	mW		
Output	Output current	Io	8	mA		
	Supply voltage	V <sub>CC</sub>	-0.5 to +30	V		
	Output voltage	Vo	-0.5 to +20	V		
	*3 Power dissipation	Po	100	mW		
*4 Isolation voltage		V <sub>iso (rms)</sub>	5.0	kV		
Operating temperature		T <sub>opr</sub>	-55 to +100	°C		
Storage temperature		T <sub>stg</sub>	-55 to +125	°C		
*5 Soldering temperature		T <sub>sol</sub>	270	°C		

#### ■ Absolute Maximum Ratings (T<sub>a</sub>=25°C

\*1 When ambient temperature goes above 70°C, the power dissipation goes down at 0.8mA/°C

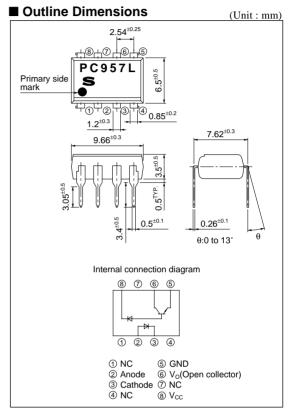
\*2 When ambient temperature goes above 70°C, the power dissipation goes down at  $0.8 mW/^{\circ}C$ 

\*3 When ambient temperature goes above 70°C, the power dissipation goes down at  $1.9 mW/^\circ C$ 

\*4 40 to 60%RH, AC for 1minute

\*5 For 10s

# High Speed and High CMR \*OPIC Photocoupler



\* "OPIC"(Optical IC) is a trademark of the SHARP Corporation. An OPIC consists of a light-detecting element and signalprocessing circuit integrated onto a single chip.

#### SHARP

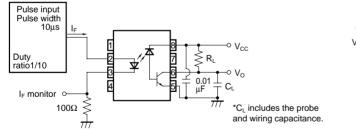
■ Electro-optical Characteristics *6 (Unless otherwise specified Ta=0 to +70°C)									
Parameter		Symbol	Conditions	MIN.	TYP.	MAX.	Unit		
Input	Forward voltage	V <sub>F</sub>	$T_a=25^{\circ}C, I_F=16mA$	_	1.7	1.95	V		
	Reverse current	I <sub>R</sub>	$T_a=25^{\circ}C, V_R=5V$		-	10	μA		
	Terminal capacitance	Ct	$T_a=25^{\circ}C$ , $V_F=0$ , f=1MHz	-	60	250	pF		
Output	High level output current (1)	I <sub>OH(1)</sub>	$T_a=25^{\circ}C$ , $I_F=0$ , $V_{CC}=V_0=5.5V$	-	3	500	nA		
	High level output current (2)	I <sub>OH (2)</sub>	$T_a=25^{\circ}C, I_F=0, V_{CC}=V_0=15V$	-	0.01	1	μΑ		
	High level output current (3)	I <sub>OH (3)</sub>	$I_{F}=0, V_{CC}=V_{O}=15V$	-	-	50	μΑ		
	Low level output voltage	VOL	$I_F=16mA$ , $V_{CC}=4.5V$ , $I_O=2.4mA$	-	0.1	0.4	V		
	Low level supply current	I <sub>CCL</sub>	I <sub>F</sub> =16mA, V <sub>CC</sub> =15V, V <sub>O</sub> =open	_	120	-	μΑ		
	High level supply current (1)	I <sub>CCH (1)</sub>	$T_a=25^{\circ}C$ , $I_F=0$ , $V_{CC}=15V$ , $V_0=open$	-	0.02	1	μA		
	High level supply current (2)	I <sub>CCH (2)</sub>	I <sub>F</sub> =0, V <sub>CC</sub> =15V, V <sub>O</sub> =open	-	-	2	μΑ		
Transfer charac- teristics	Current transfer ratio (1)	CTR (1)	T <sub>a</sub> =25°C, I <sub>F</sub> =16mA, V <sub>CC</sub> =4.5V, V <sub>O</sub> =0.4V	19	-	50	%		
	Current transfer ratio (2)	CTR (2)	$I_F=16mA$ , $V_{CC}=4.5V$ , $V_0=0.4V$	15	_	_	%		
	Isolation resistance	R <sub>ISO</sub>	T <sub>a</sub> =25°C, DC=500V, 40 to 60%RH	5×10 <sup>10</sup>	1×10 <sup>11</sup>	-	Ω		
	Floating capacitance	Cf	T <sub>a</sub> =25°C, V=0, f=1MHz	-	0.6	1	pF		
	<sup>*7</sup> "High→Low" propagation delay time	t <sub>pHL</sub>	$T_a=25^{\circ}C, V_{CC}=5V$	-	0.2	0.8	μs		
	<sup>*7</sup> "Low→High" propagation delay time	t <sub>pLH</sub>	$I_F=16mA$ , $R_L=1.9\Omega$	-	0.6	0.8	μs		
	*8 Instantaneous common mode rejection voltage "Output : High level"	CM <sub>H</sub>	$\begin{array}{l} T_a{=}25^{\circ}C,I_{F}{=}0,V_{CC}{=}5V\\ V_{CM(p{-}p)}{=}1.0kV,R_L{=}1.9k\Omega \end{array}$	15	30	_	kV/μs		
	<sup>*8</sup> Instantaneous common mode rejection voltage "Output : Low level"	CML	$\begin{array}{l} T_{a}\!\!=\!\!25^{\circ}C,I_{F}\!\!=\!\!16mA,V_{CC}\!\!=\!\!5V\\ V_{CM(p\!-\!p)}\!\!=\!\!1.0kV,R_{L}\!\!=\!\!1.9k\Omega \end{array}$	-15	-30	_	kV/μs		

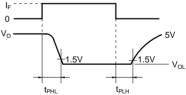
\*6 When measuring output and transfer characteristics, connect a by-pass capacitor (0.01µF or more) between Vcc (3) and GND (5) near the device

\*7 Refer to Fig.1

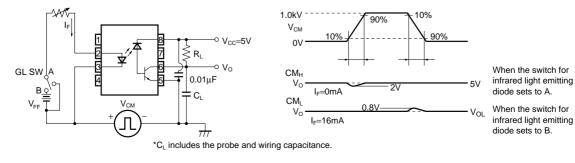
\*8 Refer to Fig.2

# Fig.1 Test Circuit for Propagation Delay Time

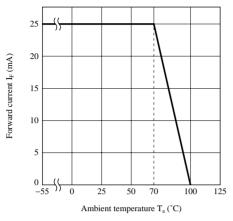




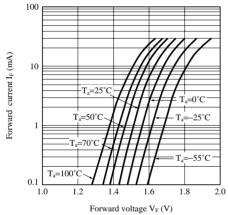
#### Fig.2 Test Circuit for Instantaneous Common Mode Rejection Voltage



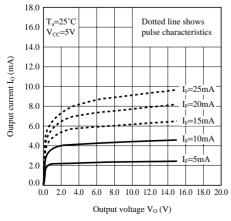
#### Fig.3 Forward Current vs. Ambient Temperature



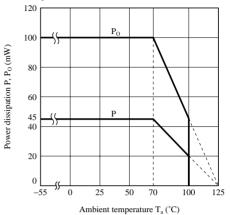




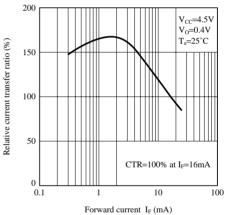




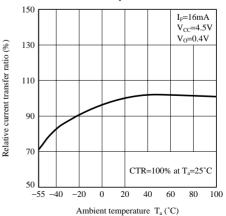
### Fig.4 Power Dissipation vs. Ambient Temperature



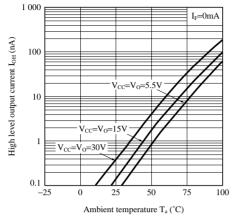
# Fig.6 Relative Current Transfer Ratio vs. Forward Current



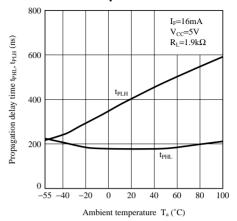
# Fig.8 Relative Current Transfer Ratio vs. Ambient Temperture



# Fig.9 High Level Output Current vs. Ambient temperature



## Fig.10 Propagetion Delay Time vs. Ambient Temperature



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